

RoHS Compliant Product
A suffix of "C" specifies halogen free

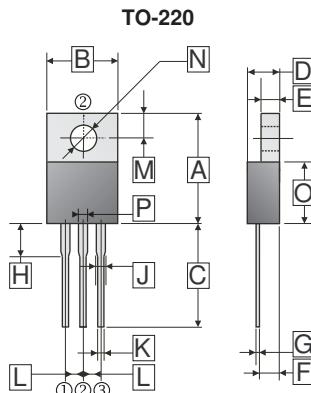
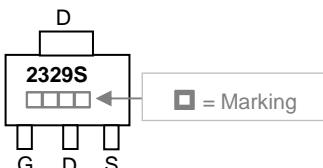
DESCRIPTION

The SGE2329S uses advanced trench technology to provide excellent on-resistance extremely efficient and cost-effectiveness device. The through-hole version is available for low-profile applications and suited for low voltage applications such as DC/DC converters.

FEATURES

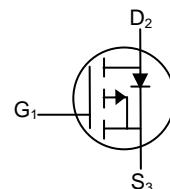
- High Density Cell Design for Ultra Low On-Resistance
- High power and Current handling capability
- Excellent CdV/dt effect decline
- 100% EAS and 100% Rg Guaranteed
- Green Device Available

PACKAGE CODE



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	14.22	16.51	J	0.7	1.78
B	9.65	10.67	K	0.38	1.02
C	12.50	14.75	L	2.39	2.69
D	3.56	4.90	M	2.50	3.43
E	0.51	1.45	N	3.10	4.09
F	2.03	2.92	O	8.38	9.65
G	0.31	0.76	P	0.89	1.47
H	3.5	4.5			

P-Channel



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ratings		Unit	
Drain-Source Voltage	V_{DS}	-100		V	
Gate-Source Voltage	V_{GS}	± 20		V	
Continuous Drain Current, $V_{GS}@10V^1$	I_D	-1.5		A	
		-1.2		A	
Pulsed Drain Current ²	I_{DM}	-5.5		A	
Total Power Dissipation ³	$T_A=25^\circ C$	P_D	2		W
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 ~ +150		°C	
Thermal Resistance Ratings					
Thermal Resistance Junction-ambient ¹	Max.	$R_{\theta JA}$	62.5		°C/W

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-Source Breakdown Voltage	BV_{DSS}	-100	-	-	V	$V_{GS}=0$, $I_D = -250\mu\text{A}$
Gate Threshold Voltage	$V_{GS(\text{th})}$	-1	-	-2.5	V	$V_{DS}=V_{GS}$, $I_D = -250\mu\text{A}$
Forward Transconductance	g_{fs}	-	3	-	S	$V_{DS} = -5\text{V}$, $I_D = -1\text{A}$
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$V_{GS} = \pm 20\text{V}$
Drain-Source Leakage Current	I_{DSS}	-	-	-1	μA	$V_{DS} = -80\text{V}$, $V_{GS}=0$
$T_J=25^\circ\text{C}$		-	-	-5	μA	
$T_J=55^\circ\text{C}$						
Static Drain-Source On-Resistance	$R_{DS(\text{ON})}$	-	-	650	m Ω	$V_{GS} = -10\text{V}$, $I_D = -1\text{A}$
		-	-	700		$V_{GS} = -4.5\text{V}$, $I_D = -0.5\text{A}$
Total Gate Charge ²	Q_g	-	9.3	-	nC	$I_D = -1\text{A}$ $V_{DS} = -50\text{V}$ $V_{GS} = -10\text{V}$
Gate-Source Charge	Q_{gs}	-	1.75	-		
Gate-Drain ("Miller") Change	Q_{gd}	-	1.25	-		
Turn-on Delay Time ²	$T_{d(on)}$	-	2	-		
Rise Time	T_r	-	18.4	-	ns	$V_{DD} = -50\text{V}$ $I_D = -0.5\text{A}$ $V_{GS} = -10\text{V}$ $R_G = 3.3\Omega$ $R_L = 30\Omega$
Turn-off Delay Time	$T_{d(off)}$	-	19.6	-		
Fall Time	T_f	-	19.6	-		
Input Capacitance	C_{iss}	-	513	-	pF	$V_{GS} = 0\text{V}$ $V_{DS} = -15\text{V}$ $f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	-	29	-		
Reverse Transfer Capacitance	C_{rss}	-	17	-		
Source-Drain Diode						
Forward On Voltage ²	V_{SD}	-	-	-1.2	V	$I_S = -1\text{A}$, $V_{GS} = 0\text{V}$, $T_J = 25^\circ\text{C}$
Continuous Source Current ^{1,4}	I_S	-	-	-1.5	A	$V_D = V_G = 0\text{V}$, Force Current
Pulsed Source Current ^{2,4}	I_{SM}	-	-	-5	V	
Reverse Recovery Time	T_{rr}	-	27	-	nS	$I_F = -1\text{A}$, $T_J = 25^\circ\text{C}$
Reverse Recovery Charge	Q_{rr}	-	36	-	nC	$dI/dt = 100\text{A}/\mu\text{s}$

Notes:

1. The data tested by surface mounted on a inch² FR-4 board with 2OZ copper.
2. The data tested by pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
3. The power dissipation is limited by 150°C junction temperature.
4. The data is theoretically the same as ID and IDM, In real applications, should be limited by total power dissipation.

CHARACTERISTICS CURVE

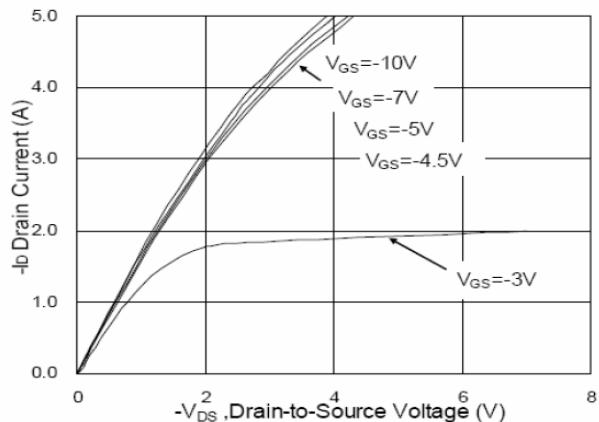


Fig.1 Typical Output Characteristics

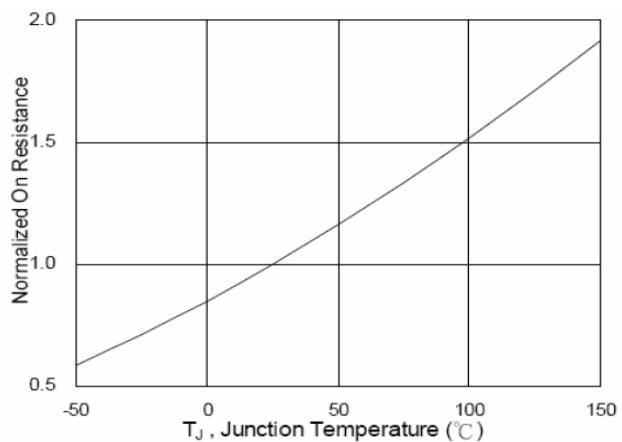


Fig.2 Normalized $R_{DS(on)}$ vs. T_J

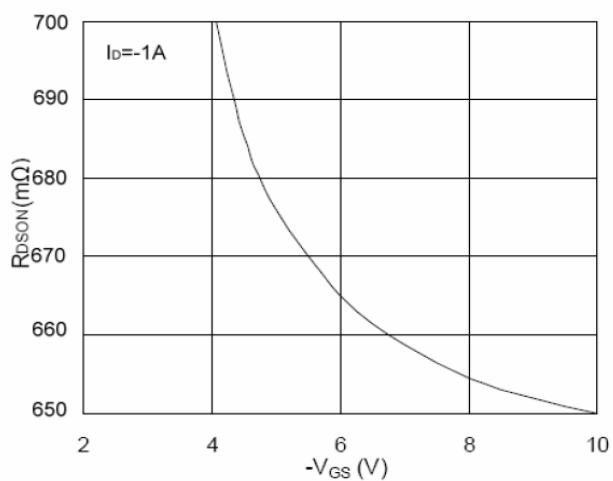


Fig.3 On-Resistance vs. G-S Voltage

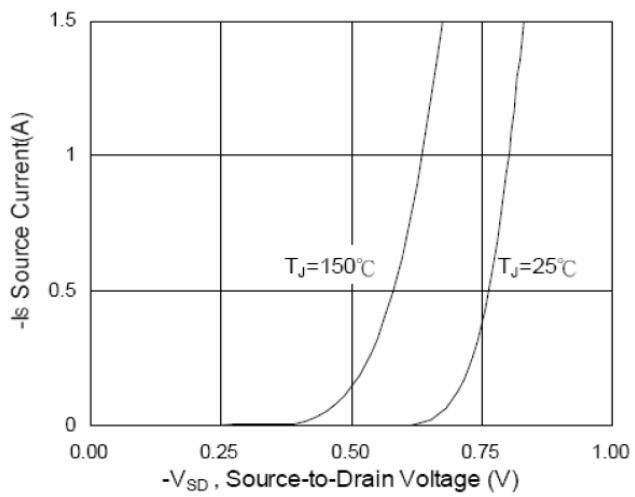


Fig.4 Forward Characteristics of Reverse

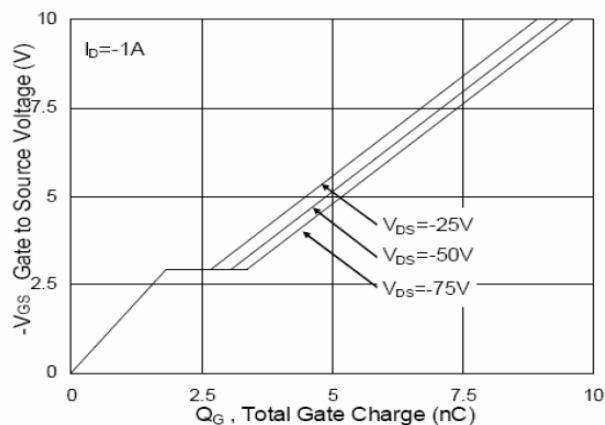


Fig.5 Gate-Charge Characteristics

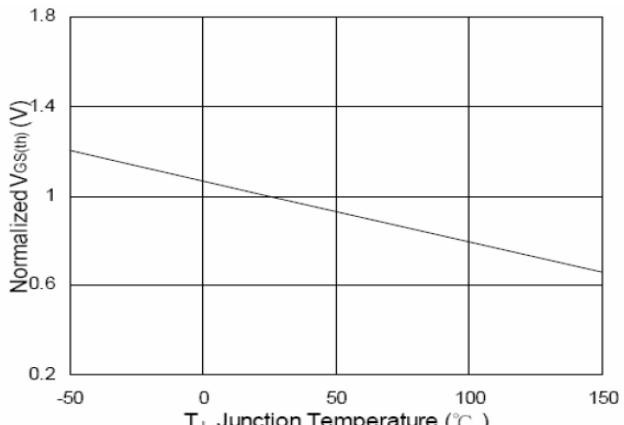


Fig.6 Normalized $V_{GS(th)}$ vs. T_J

CHARACTERISTIC CURVE

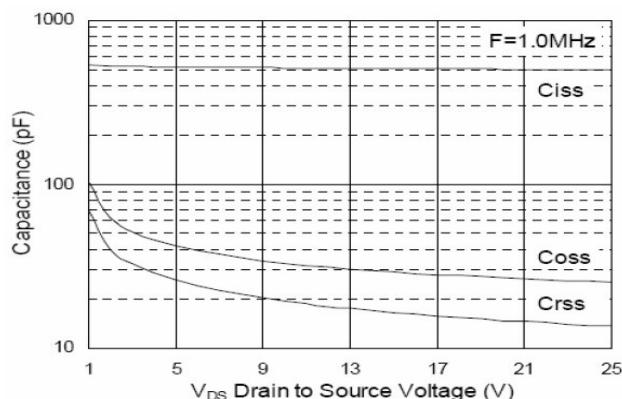


Fig.7 Capacitance

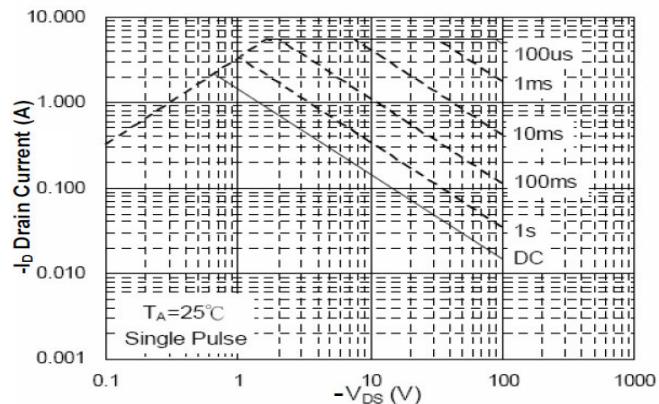


Fig.8 Safe Operating Area

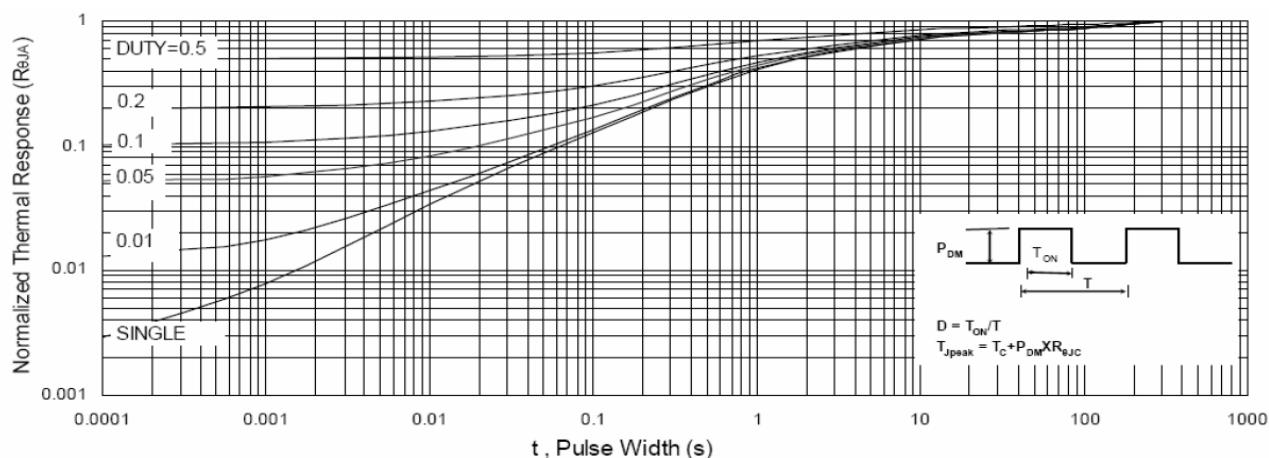


Fig.9 Normalized Maximum Transient Thermal Impedance

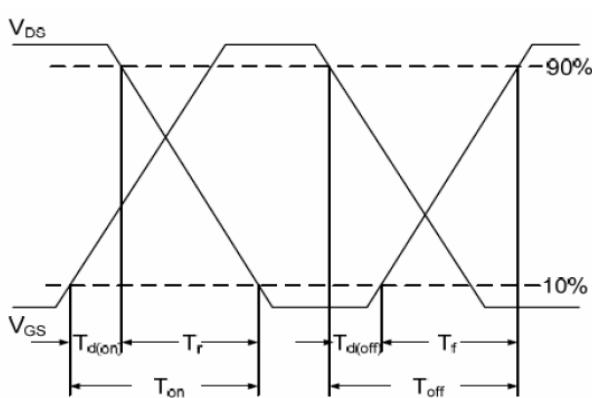


Fig.10 Switching Time Waveform

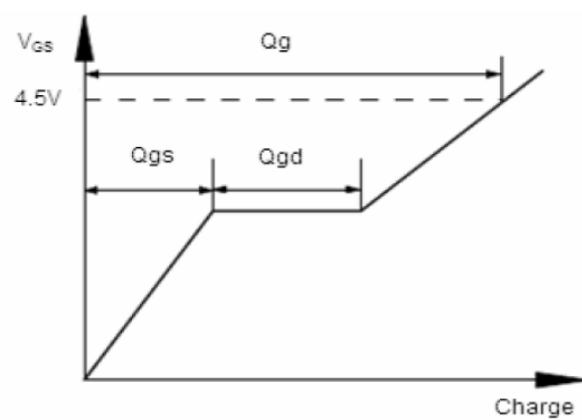


Fig.11 Gate Charge Waveform